

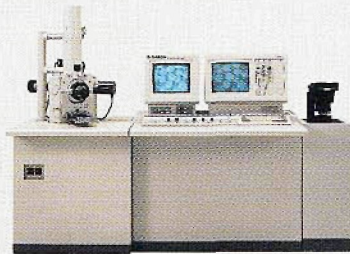
Introducing the “any specimen,” “no preparation” SEM.

Wet specimens. Oily specimens.
Non-conductive specimens. Foods.
Pharmaceuticals. Plant life. Semiconductors. Polymers. Cosmetics. Textiles. Biological and geological specimens.

In fact, just name the specimen. We have your SEM. It's Hitachi's Variable Pressure S-2460N, the SEM that ends tedious specimen preparation such as drying or sputter coating for conductivity. Instead, specimens are observed in their natural, unaltered state—specimens up to 150 mm in diameter.

What's more, the S-2460N's low-vacuum mode comes without

tradeoffs in performances, tradeoffs you'd face even in the costliest of other systems. At magnifications up to 200,000X, you'll have 6.0 nm resolution in low-vacuum operation, 4.0 nm in high vacuum.



resolution images are obtained at the touch of a button.

More good news. This SEM costs little more than a top-notch optical

microscope. And its sharp images and repeatable results come with features like digital frame memory and image processing; you can even add any of various analytical spectrometers. Better call or write for details. And ask for a demonstration of the “any specimen,” “no preparation” SEM. There's nothing else like it.

Further, the S-2460N is as easy to use as an optical microscope. No expertise or training needed. The vacuum system is computer controlled; high-

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VISION goes beyond mere computer control. Computer control of an SEM really has little value unless it makes your life easier by making the instrument easier and faster to control, gives you things like digital high resolution (1024 X 910) image archiving to optical disk, a unique visually oriented

stage control system, SEM parameter data transfer, remote access and LAN compatibility, and much more. With VISION, you get to choose the way you operate each instrument control – keyboard, knobset and or trackball – simultaneously. This is real versatility and makes the JSM-6000 Series VISION a true productivity SEM.

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